

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10575489	FUKSHIMA ET AL.
	Examiner	Art Unit
	Conley, Robert	2891

SEARCHED

Class	Subclass	Date	Examiner
216	24, 41	8/30/2007	RTC
257	25, 81, 91, 95, 98-100, 103	8/30/2007	RTC
438	22, 46, 47, 918, 9	8/30/2007	RTC

SEARCH NOTES

Search Notes	Date	Examiner
Fukshima Kubo Inoue Tanaka Masui Matsui	8/30/2007	RTC
((257/98-100).ccls. (257/91).ccls. (257/103).ccls. (257/95).ccls. (216/24).ccls. (216/41).ccls. (438/22).ccls. (438/46-47).ccls.) and ((light-emitting lightemitting light adj emitting)adj diode and (enhance\$3 with light with extract\$4) and ((rough\$3 adj surface adj structure) (rough\$3 adj interface) (interfac\$2 with textur\$3) (random\$3 adj grat\$3 adj structure) (protrusion\$2 same cones with pyramid\$4) (order\$2 with textur\$3 with interface) (textur\$3 adj (photoresist photo-resist photo adj resist	8/30/2007	RTC
((light-emitting lightemitting light adj emitting)adj diode and (silicon with organi\$3 with solven\$3)).bi.	8/30/2007	RTC
((light-emitting lightemitting light adj emitting)adj diode and (silicon with organi\$3 with solven\$3) and (silicon adj alkoxide TMOS TEOS)).bi.	8/30/2007	RTC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner